Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/019,250	NAKAMURA ET AL.	
Examiner	Art Unit	
ISU NA CERNA	1774	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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